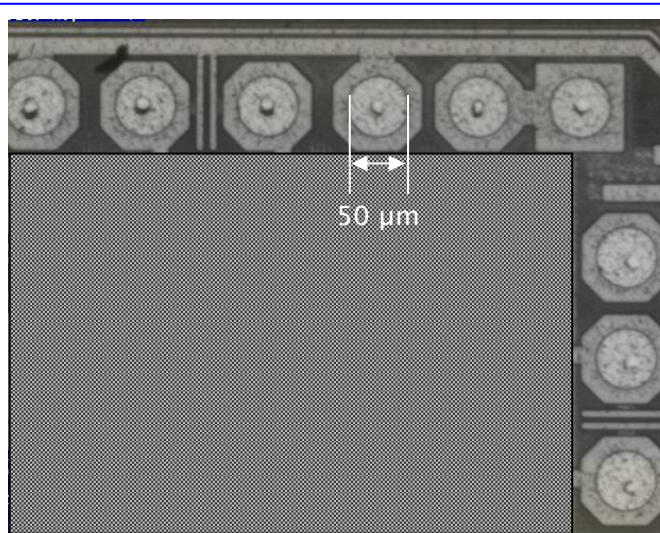


## Advanced Cantilever – ShortScrub / NoScrub Probe Cards for Small Pad Dimensions, Parametric Test, Pad Over Active Area (POAA)

Ever decreasing pad sizes for parametric test going together with shrinking scribe line width provide increasing challenges for contacting. On the other hand Pads Over Active Area (POAA) demand small mechanical stress on impact of the probes

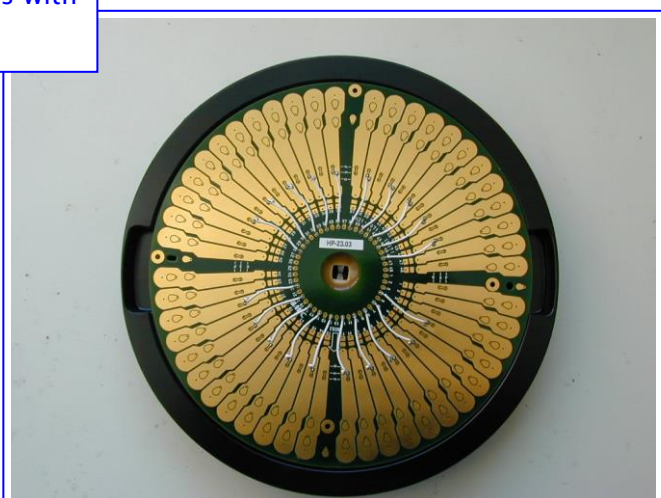


Scrub marks on 50 µm diameter bond pads with ShortScrub/fine probe card <sup>1)</sup>

T.I.P.S.' unique probe shape and FEM designed probes allow for minimal scrub mark sizes yet maintaining excellent contact properties

➤ "ShortScrub / NoScrub" technology allows for contacting pads as small as 30x30 µm with well proven and economy-priced cantilever probe cards

A proprietary probe tip reshaping and maintenance process ensures the full performance of the probe card over the life span - either by T.I.P.S. maintenance services or by equipment that can be provided for customers on-site probe card shop.



Parametric probe card for 4080 Tester

1) Photo courtesy by NXP Semiconductors